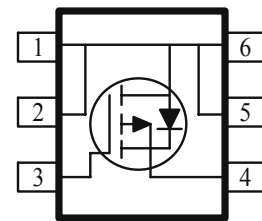
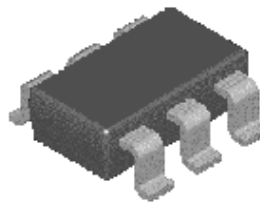


AM3459P

These miniature surface mount MOSFETs utilize High Cell Density process. Low $r_{DS(on)}$ assures minimal power loss and conserves energy, making this device ideal for use in power management circuitry. Typical applications are PWMDC-DC converters, power management in portable and battery-powered products such as computers, printers, battery charger, telecommunication power system, and telephones power system.

- Low $r_{DS(on)}$ Provides Higher Efficiency and Extends Battery Life
- Miniature SO-8 Surface Mount Package Saves Board Space
- High power and current handling capability
- Extended VGS range (± 25) for battery pack applications



| PRODUCT SUMMARY | | |
|-----------------|---------------------------|-----------|
| V_{DS} (V) | $r_{DS(on)}$ (Ω) | I_D (A) |
| -60 | 0.310 @ $V_{GS} = -10V$ | 2.1 |
| | 0.465 @ $V_{GS} = -4.5V$ | 1.7 |

| ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ UNLESS OTHERWISE NOTED) | | | | |
|---|--------------------|----------------|------------|------------|
| Parameter | | Symbol | Maximum | Units |
| Drain-Source Voltage | | V_{DS} | -60 | V |
| Gate-Source Voltage | | V_{GS} | ± 20 | |
| Continuous Drain Current ^a | $T_A = 25^\circ C$ | I_D | 2.1 | A |
| | $T_A = 70^\circ C$ | | 1.7 | |
| Pulsed Drain Current ^b | | I_{DM} | ± 15 | |
| Continuous Source Current (Diode Conduction) ^a | | I_S | -1.7 | A |
| Power Dissipation ^a | $T_A = 25^\circ C$ | P_D | 2.0 | W |
| | $T_A = 70^\circ C$ | | 1.3 | |
| Operating Junction and Storage Temperature Range | | T_J, T_{stg} | -55 to 150 | $^\circ C$ |

| THERMAL RESISTANCE RATINGS | | | | |
|--|----------------|-----------------|---------|--------------|
| Parameter | | Symbol | Maximum | Units |
| Maximum Junction-to-Ambient ^a | $t \leq 5$ sec | $R_{\theta JA}$ | 62.5 | $^\circ C/W$ |
| | | | 110 | $^\circ C/W$ |

Notes

- Surface Mounted on 1" x 1" FR4 Board.
- Pulse width limited by maximum junction temperature



| SPECIFICATIONS (T _A = 25°C UNLESS OTHERWISE NOTED) | | | | | | |
|---|---------------------|---|--------|-----|------|------|
| Parameter | Symbol | Test Conditions | Limits | | | Unit |
| | | | Min | Typ | Max | |
| Static | | | | | | |
| Gate-Threshold Voltage | V _{GS(th)} | V _{DS} = V _{GS} , I _D = -250 uA | -1 | | | |
| Gate-Body Leakage | I _{GSS} | V _{DS} = 0 V, V _{GS} = ±20 V | | | ±100 | nA |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} = -48 V, V _{GS} = 0 V | | | -1 | uA |
| | | V _{DS} = -48 V, V _{GS} = 0 V, T _J = 55°C | | | -10 | |
| On-State Drain Current ^A | I _{D(on)} | V _{DS} = -5 V, V _{GS} = -10 V | -20 | | | A |
| Drain-Source On-Resistance ^A | r _{DS(on)} | V _{GS} = -10 V, I _D = -2.1 A | | | 310 | mΩ |
| | | V _{GS} = -4.5 V, I _D = -1.7 A | | | 465 | |
| Forward Transconductance ^A | g _f | V _{DS} = -15 V, I _D = -2.1 A | | 8 | | S |
| Diode Forward Voltage | V _{SD} | I _S = -2.5 A, V _{GS} = 0 V | | | -1.2 | V |
| Dynamic^b | | | | | | |
| Total Gate Charge | Q _g | V _{DS} = -30 V, V _{GS} = -4.5 V, I _D = -2.1 A | | 18 | | nC |
| Gate-Source Charge | Q _{gs} | | | 5 | | |
| Gate-Drain Charge | Q _{gd} | | | 2 | | |
| Turn-On Delay Time | t _{d(on)} | V _{DD} = -30 V, R _L = 30 Ω, I _D = -1 A, V _{GEN} = -10 V, R _G = 6Ω | | 8 | | nS |
| Rise Time | t _r | | | 10 | | |
| Turn-Off Delay Time | t _{d(off)} | | | 35 | | |
| Fall-Time | t _f | | | 12 | | |

Notes

- a. Pulse test: PW ≤ 300us duty cycle ≤ 2%.
- b. Guaranteed by design, not subject to production testing.